## Notice of References Cited Application/Control No. | Applicant(s)/Patent Under | Reexamination | DEY ET AL. | Examiner | Art Unit | Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2002/0034267 A1	03-2002	Chuang et al.	375/340
*	В	US-6,389,087 B1	05-2002	Heinonen et al.	375/354
*	С	US-6,654,429 B1	11-2003	Li, Ye	375/316
*	D	US-2004/0141457 A1	07-2004	Seo et al.	370/203
*	E	US-2003/0128751 A1	07-2003	Vandenameele-Lepla, Patrick	375/229
*	F	US-2004/0022174 A1	02-2004	Li et al.	370/203
*	G.	US-2006/0034380 A1	02-2006	Li, Ye	375/260
	Ι	US-			
	ı	US-			
	٦	US-			
	к	US-	,	·	
	L	US-			
	М	US-		•	

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	P	·		·		
	α					
	R					
	s					
	Т					

## **NON-PATENT DOCUMENTS**

	HOIST ATENT BOOMENTO						
*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)					
	U						
	V						
	w	,					
	×						

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.